

Search Notes

Application/Control No.

10/602,325

Examiner

Brian S. Kwon

Applicant(s)/Patent under
Reexamination

CHAPLIN ET AL.

Art Unit

1614

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR